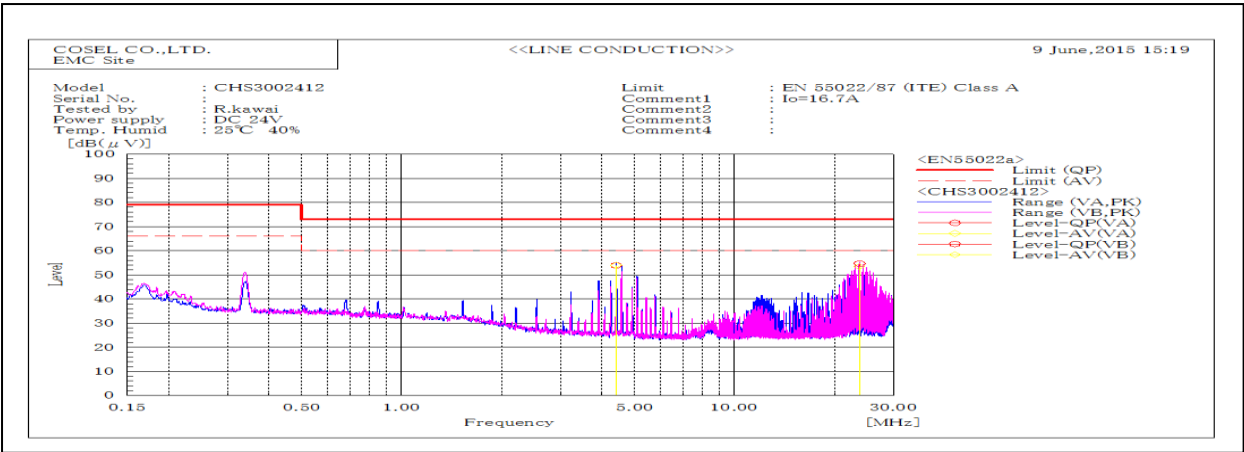
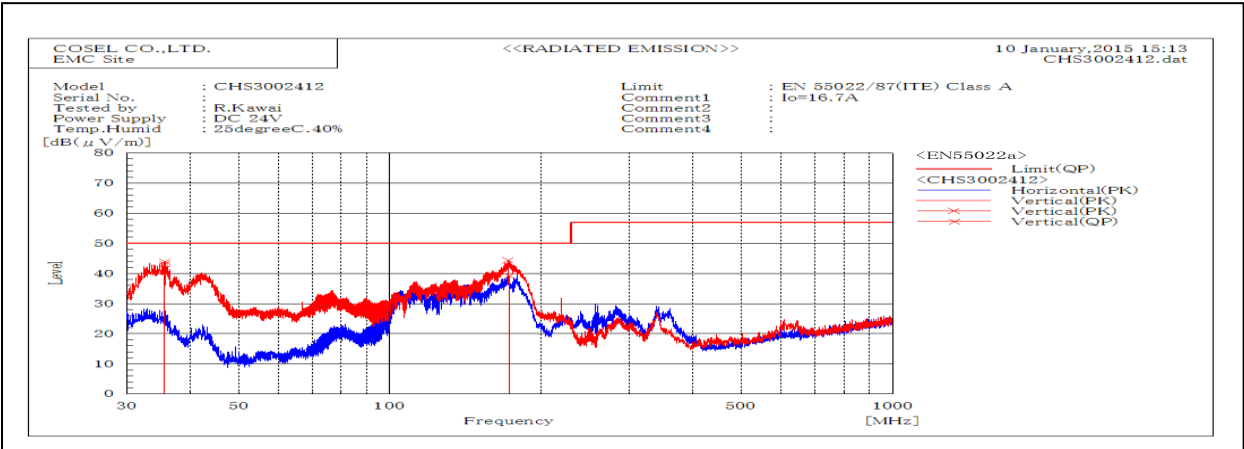


DATA SHEET		Date	10-Jun-15
Model	CHS3002412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



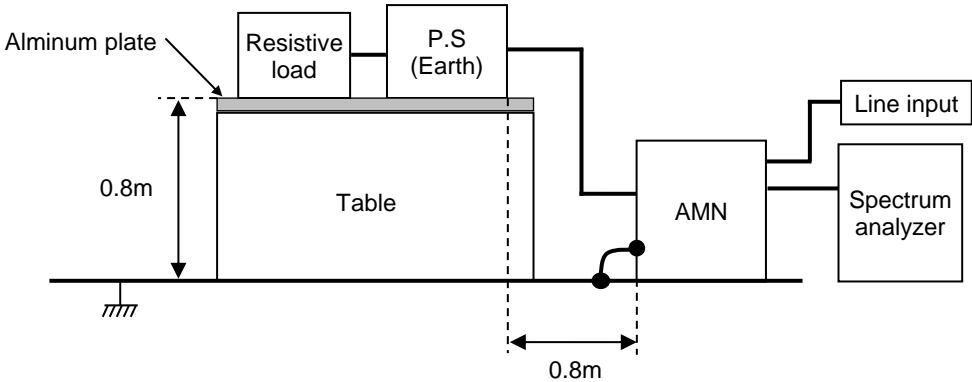
Frequency MHz	Ham	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
4.41082		VA	33.7	33.8	20.2	53.9	54	73	60	19.1	6	Pass	
23.7608		VB	33.8	32.5	20.9	54.7	53.4	73	60	18.3	6.6	Pass	



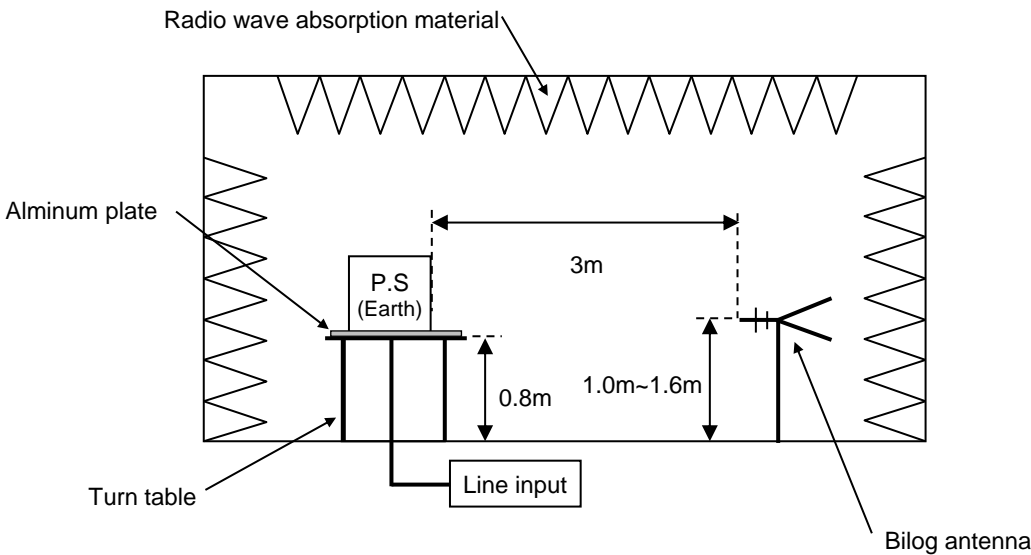
Frequency MHz	Polariz ation	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
35.638	V	Stable	58.1	-14.9	43.2	50	6.8	Pass	101	224	
172.578	V	Stable	55.3	-16.1	39.2	50	10.8	Pass	128	340	

DATA SHEET		Date	10-Jun-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission



Conditions

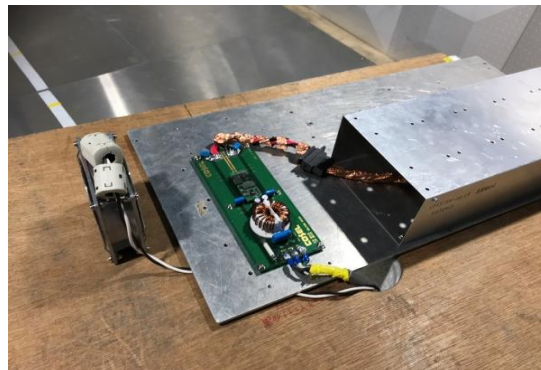
Test : EMI
Model Name : CHS30024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

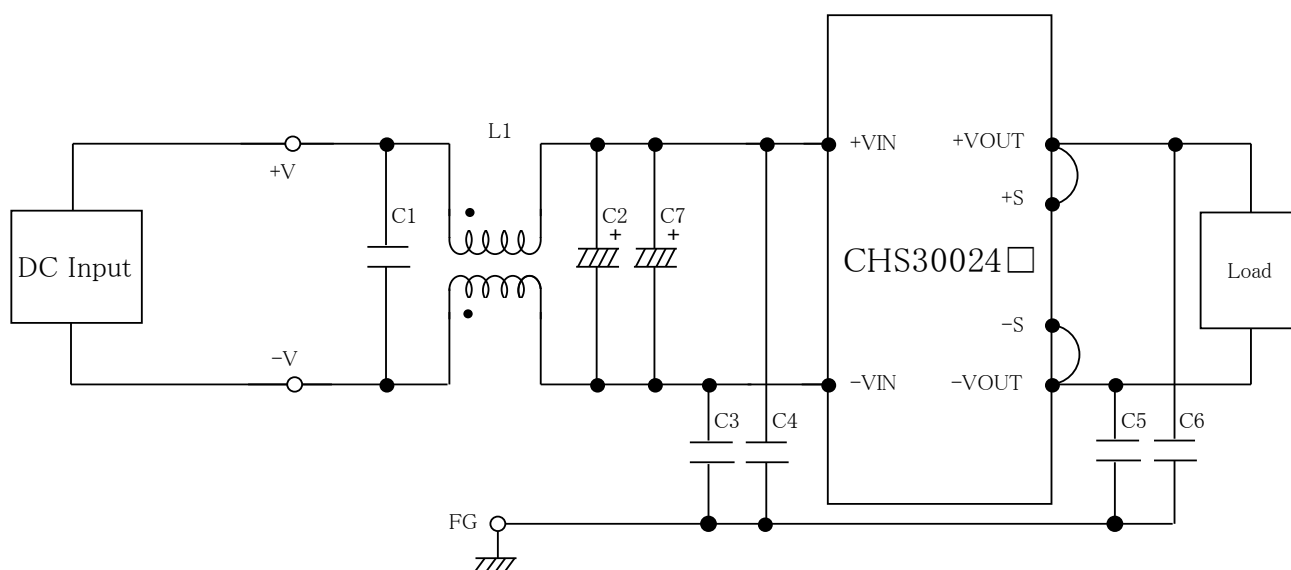


Fig.1 Testing circuitry

L1 : 1mH SC-20-10JH (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 50V 330 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)